

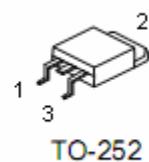
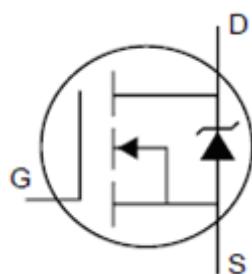
## 1. Features

- Advanced trench process technology
- High density cell design for ultra low on-resistance
- Fully characterized avalanche voltage and current

## 2. Applications

- $V_{DSS}=30V, R_{DS(on)}=8.0m\Omega, I_D=50A$
- $V_{ds}=30V$
- $R_{DS(ON)}=8.0m\Omega(\text{Max.}), V_{GS} @ 10V, I_{ds} @ 30A$
- $R_{DS(ON)}=9.5m\Omega(\text{Max.}), V_{GS} @ 4.5V, I_{ds} @ 30A$

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

## 4. Maximum ratings and thermal characteristics

(Ta=25°C,unless otherwise notes)

Rating	Symbol	Value	Unit	
Drain-source voltage	V <sub>DS</sub>	30	V	
Gate-source voltage	V <sub>GS</sub>	$\pm 20$	V	
Continuous drain current	I <sub>D</sub>	50	A	
Pulsed drain current <sup>1)</sup>	I <sub>DM</sub>	200	A	
Maximum power dissipation	T <sub>A</sub> =25°C	P <sub>D</sub>	60	W
	T <sub>A</sub> =75°C	P <sub>D</sub>	23	W
Operating junction and storage temperature range	T <sub>J/T<sub>STG</sub></sub>	-55 to 150	°C	
Junction-to-case thermal resistance	R <sub>θJC</sub>	1.8	°C/W	
Junction-to ambient thermal resistance (PCB mount) <sup>2)</sup>	R <sub>θJA</sub>	50	°C/W	

Note:1.Repetitive rating:pulse width limited by the maximum junction tempereration

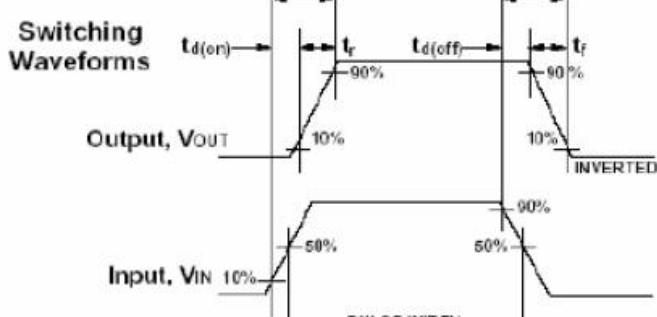
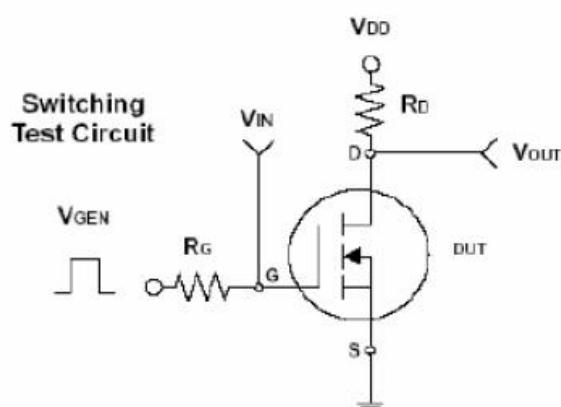
2.1-in<sup>2</sup> 2oz Cu PCB board

3.Guaranteed by design;not subject to production testing

## 5. Ordering information

Part number	Package
50N03	TO-252

## 6. Typical application circuit





## 7. Electrical characteristics

(Ta=25°C,unless otherwise notes)

Parameter	Symbol	Test conditions	Min.	Typ.	Max.	Units
<b>Static</b>						
Drain-source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V,I <sub>D</sub> =250μA	30	-	-	V
Drain-source on-state resistance em	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V,I <sub>D</sub> =30A	-	9.5	13.0	mΩ
		V <sub>GS</sub> =10V,I <sub>D</sub> =30A	-	8.0	9.0	mΩ
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =-250μA	1	1.8	3	V
Forward transconductance	g <sub>fs</sub>	V <sub>DS</sub> =15V,I <sub>D</sub> =15A	-	12	-	S
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-source forward leakage	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
<b>Dynamic<sup>3)</sup></b>						
Total gate charge	Q <sub>g</sub>	I <sub>D</sub> =35A V <sub>DS</sub> =15V V <sub>GS</sub> =10V	-	10	25	nC
Gate-source charge	Q <sub>gs</sub>		-	3.5	10	nC
Gate-drain (“miller”)charge	Q <sub>gd</sub>		-	3	65	nC
Turn-on delay time	t <sub>d(off)</sub>	V <sub>DD</sub> =15V I <sub>D</sub> =1A R <sub>G</sub> =6Ω R <sub>L</sub> =15Ω V <sub>GEN</sub> =10V	-	12	-	ns
Rise time	t <sub>r</sub>		-	4	-	ns
Turn-off delay time	t <sub>d(off)</sub>		-	32	-	ns
Fall time	t <sub>f</sub>		-	6	-	ns
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V V <sub>DS</sub> =15V f=1.0MHz	-	1180	-	pF
Output capacitance	C <sub>oss</sub>		-	270	-	pF
Reverse transfer capacitance	C <sub>rss</sub>		-	145	-	pF

### Source-drain diode

Parameter	Symbol	Test condition	Min.	Typ.	Max.	Units
Diode forward voltage	V <sub>SD</sub>	I <sub>s</sub> =20A,V <sub>GS</sub> =0V	-	0.87	1.5	V
Max.diode forward current	I <sub>s</sub>		-	-	20	A

Notes:Pulse width≤300μs,duty cycle≤2%